

PROCEEDINGS OF SPIE

Thermosense XXX

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Douglas D. Burleigh
Editors

18–20 March 2008
Orlando, Florida, USA

Sponsored and Published by
SPIE

Volume 6939

Proceedings of SPIE, 0277-786X, v. 6939

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Author(s), "Title of Paper," in *Thermosense XXX*, edited by Vladimir P. Vavilov, Douglas D. Burleigh, Proceedings of SPIE Vol. 6939 (SPIE, Bellingham, WA, 2008) Article CID Number.

ISSN 0277-786X
ISBN 9780819471307

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445
SPIE.org

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Printed in the United States of America.

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Contents

ix *Conference Committee*

SESSION 1 PYROMETRY, TEMPERATURE MEASUREMENTS, AND CALIBRATION I

- 6939 02 **Infrared micro-thermography of an actively heated preconcentrator device** [6939-01]
R. Furstenberg, C. A. Kendziora, S. V. Stepnowski, D. R. Mott, R. A. McGill, Naval Research Lab. (USA)
- 6939 03 **High temperature IR-imager with wide dynamic range for industrial process control** [6939-02]
U. Hoffmann, G. Hofmann, D. Wassilew, N. Heß, M. Zimmerhackl, DIAS Infrared GmbH (Germany)
- 6939 04 **Emissivity independent low-temperature pyrometry** [6939-03]
I. Dolezal, L. Hes, Technical Univ. of Liberec (Czech Republic)

SESSION 2 PYROMETRY, TEMPERATURE MEASUREMENTS, AND CALIBRATION II

- 6939 06 **Infrared calibration development at Fluke Corporation Hart Scientific Division** [6939-05]
F. Liebmann, Fluke Corp. (USA)
- 6939 08 **IEC 62942-1 TS: First international technical specification on the technical data for radiation thermometers** [6939-53]
J. Hollandt, Physikalisch-Technische Bundesanstalt (Germany); O. Struss, Heitronics Infrarot Messtechnik GmbH (Germany); G. Beynon, Land Instruments International (United Kingdom); R. Bosma, NMI Van Swinden Laboratorium B. V. (Netherlands); R. Gaertner, Raytek GmbH (Germany); F. Girard, Istituto Nazionale di Ricerca Metrologica (Italy); M. S. Matveyev, D.I. Mendeleev Institute for Metrology (Russia); H. C. McEvoy, National Physical Lab. (United Kingdom); G. R. Peacock, Temperatures.com, Inc. (USA); M. Sadli, Lab. National de Metrologie et d'Essais INM/CNAM (France); F. Sakuma, National Metrology Institute of Japan (Japan); H. W. Yoon, National Institute of Standards and Technology (USA); Z. Yuan, National Institute of Metrology (China)

SESSION 3 PROFESSIONAL STANDARDS I

- 6939 09 **Do infrared thermographers need a professional organization?** [6939-07]
G. R. Peacock, Temperatures.com, Inc. (USA)
- 6939 0A **Certification of thermographers** [6939-08]
J. Snell, R. Spring, The Snell Group (USA)

SESSION 4 PROFESSIONAL STANDARDS II

- 6939 0B **International standards pertaining to thermography practices, training and certification** [6939-09]
L. West Åkerblom, FLIR Systems AB (Sweden)

SESSION 5 THERMAL IMAGE FUSION

- 6939 0F **Image fusion: multi-focus function and its application** [6939-13]
Y. Kimura, A. Ichikawa, Nippon Avionics Co., Ltd. (Japan); T. Tamura, K. Endo, NEC San-ei Instruments (Japan)

SESSION 6 IR NEIGHBORS: NIR, VISIBLE AND UV I

- 6939 0H **Industrial defect discrimination applying infrared imaging spectroscopy and artificial neural networks** [6939-15]
P. B. Garcia-Allende, O. M. Conde, F. J. Madruga, A. M. Cubillas, J. M. Lopez-Higuera, Univ. de Cantabria (Spain)
- 6939 0I **Overview of SWIR detectors, cameras, and applications** [6939-16]
M. P. Hansen, D. S. Malchow, SUI, Goodrich Corp. (USA)
- 6939 0J **Calibration of visible and near infrared spectrums for measuring freshness of vegetables** [6939-17]
F. Abdullah, Univ. Sains Malaysia (Malaysia) and Syiah Kuala Univ. (Indonesia);
M. Z. Mat Jafri, M. S. Jaafar, C. J. Wong, Univ. Sains Malaysia (Malaysia)

SESSION 7 IR NEIGHBORS: NIR, VISIBLE AND UV II

- 6939 0K **High-voltage electrical survey advances using UV/IR** [6939-18]
D. A. Ninedorf, Ox Creek Energy Associates, Inc. (USA); R. Stolper, J. Hart, Council for Scientific and Industrial Research (South Africa)
- 6939 0L **Overview of expanding the longwave NDT into the shortwave spectrum below visible** [6939-19]
J. K. Eklund, EKLUND INFRARED/Eklund Innovation Inc. (USA)

SESSION 8 RESEARCH TOPICS

- 6939 0M **Thermography investigations and numerical analysis of turbulent and laminar flow at light weight structures** [6939-20]
R. Arndt, Federal Institute for Materials Research and Testing (BAM) (Germany); A. Gaulke, Technical Univ. of Berlin (Germany)
- 6939 0N **Emissivity modulating electrochromic device** [6939-21]
H. Demiryont, K. Shannon III, Eclipse Energy Systems, Inc. (USA); A. Williams, Air Force Research Lab. (USA)

6939 0O **Using lock-in infrared thermography for the visualization of the hand vascular tree** [6939-22]
N. Bouzida, A. H. Bendada, J.-M. Piau, M. Akhloufi, X. Maldague, M. Raymond, Laval Univ.
(Canada)

6939 0P **Active thermography for potato characterization** [6939-23]
S.-J. Hsieh, C.-C. Sun, Texas A&M Univ. (USA)

SESSION 9 PRODUCTS AND PROCESSES

6939 0Q **Arc welding quality monitoring by means of near infrared imaging spectroscopy** [6939-24]
P. B. Garcia-Allende, J. Mirapeix, A. Cobo, O. M. Conde, J. M. Lopez-Higuera, Univ.
de Cantabria (Spain)

6939 0R **Infrared thermography applied for outdoor power substations** [6939-25]
L. dos Santos, Furnas Centrais Elétricas (Brazil); E. C. Bortoni, L. E. Souza, G. S. Bastos,
M. A. C. Craveiro, Itajubá Federal Univ. (Brazil)

SESSION 10 ENVIRONMENTAL INVESTIGATIONS

6939 0S **Aerial measurements of convection cell elements in heated lakes** [6939-27]
E. Villa-Aleman, S. R. Salaymeh, T. B. Brown, A. J. Garret, L. S. Nichols, M. M. Pendergast,
Savannah River National Lab. (USA)

6939 0T **Direct measurement of heat flux from cooling lake thermal imagery** [6939-26]
A. J. Garrett, E. Villa-Aleman, R. J. Kurzeja, M. M. Pendergast, Savannah River National Lab.
(USA)

SESSION 11 NDT OF BUILDINGS AND CIVIL STRUCTURES

6939 0U **Thermography as a tool for building applications and diagnostics** [6939-29]
N. P. Avdelidis, Metallurgical Industrial Research & Technology Development Ctr. (Greece);
T. K. Kauppinen, Technical Research Ctr. of Finland (Finland)

6939 0V **A nondestructive method for diagnosis of insulated building walls using infrared thermography in real situation** [6939-30]
M. H. A. Larbi Youcef, A. Mazioud, C.E.R.T.E.S., IUT, Univ. Paris XII (France); P. Bremond,
Cedip Infrared Systems (France); L. Ibos, Y. Candau, C.E.R.T.E.S., IUT, Univ. Paris XII (France);
M. Piro, EDF R&D (France); A. Filloux, Alpheeis (France)

6939 0W **Crack detection and fatigue related delamination in FRP composites applied to concrete**
[6939-31]
J. Brown, R. Baker, L. Kallemeyn, A. Zender, Hope College (USA)

6939 0X **Square pulse thermography in frequency domain** [6939-32]
R. Arndt, Federal Institute for Materials Research and Testing (BAM) (Germany)

- 6939 0Y **Building material characterization by using IR thermography for efficient heating systems** [6939-33]
P. Bison, E. Grinzato, CNR-ITC (Italy)
- 6939 10 **Quantitative evaluation of defect depth in concrete structures using Fourier analysis for sequential thermal data** [6939-35]
S. Nakamura, Sumitomo-Osaka Cement Co., Ltd. (Japan); T. Sakagami, Osaka Univ. (Japan); S. Harada, Sumitomo-Osaka Cement Co., Ltd. (Japan); S. Kubo, Osaka Univ. (Japan)
- 6939 11 **Localization of wood floor structure by infrared thermography** [6939-54]
C. Cochior Plescanu, M. Klein, C. Ibarra-Castanedo, A. Bendada, X. Maldague, Univ. Laval (Canada)

SESSION 12 NDT NUMERICAL ANALYSIS AND THEORY

- 6939 13 **Accuracy issues in modeling thermal NDT problems** [6939-37]
V. Vavilov, Tomsk Polytechnic Univ. (Russia); S. Marinetti, ITC-CNR (Italy); D. Nesteruk, Tomsk Polytechnic Univ. (Russia)
- 6939 14 **A straightforward graphical user interface for basic and advanced signal processing of thermographic infrared sequences** [6939-38]
M. T. Klein, C. Ibarra-Castanedo, X. P. Maldague, A. Bendada, Univ. Laval (Canada)
- 6939 15 **Thermographic signal processing through correlation operators in pulsed thermography** [6939-39]
M. T. Klein, C. Ibarra-Castanedo, A. Bendada, X. P. Maldague, Univ. Laval (Canada)
- 6939 16 **Quantitative characterization of resistive defects in thick composites using step heating thermography** [6939-40]
A. A. Badghaish, D. C. Fleming, Florida Institute of Technology (USA)

SESSION 13 NDT METHODS AND APPLICATIONS

- 6939 18 **A study of active thermography approaches for the non-destructive testing and evaluation of aerospace structures** [6939-42]
N. P. Avdelidis, National Technical Univ. of Athens (Greece); C. Ibarra-Castanedo, Univ. Laval (Canada); Z. P. Marioli-Riga, Hellenic Aerospace Industry (Greece); A. Bendada, X. P. V. Maldague, Univ. Laval (Canada)
- 6939 19 **Fuselage inspection of Boeing 737 using lock-in thermography** [6939-43]
M. Tarin, MovIMED (USA); A. Kasper, Automation Technology GmbH (Germany)

SESSION 14 MATERIALS EVALUATION: THERMAL AND FATIGUE PROPERTIES

- 6939 1F **Detection of delamination defect inside timber by sonic IR** [6939-49]
M. Y. Choi, J. H. Park, Korea Research Institute of Standards and Science (South Korea); W. T. Kim, Kongju National Univ. (South Korea); K. S. Kang, Korea Research Institute of Standards and Science (South Korea)

- 6939 1G **Thermal stress analysis of a circular holed specimen** [6939-50]
W. T. Kim, Kongju National Univ. (South Korea); M. Y. Choi, J. H. Park, K. S. Kang, Korea
Research Institute of Standards and Science (South Korea)
- 6939 1H **Simulating thermal NDT of bonded structures by FEM** [6939-51]
X. Guo, F. Qie, Beihang Univ. (China)
- 6939 1I **Dimensionless heat transfer model to compress and analyze pulsed thermography data for
NDT of materials** [6939-52]
J. C. Ramirez-Granados, G. Paez, M. Strojnik, Ctr. de Investigaciones en Optica, A.C.
(Mexico)

Author Index

Conference Committee

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Gregory R. Stockton, Stockton Infrared Thermographic Services, Inc.
(USA)
Lisa West Åkerblom, FLIR Systems AB (Sweden)

Session Chairs

- 1 Pyrometry, Temperature Measurements, and Calibration I
G. Raymond Peacock, Temperatures.com, Inc. (USA)
Robert P. Madding, FLIR Systems, Inc. (USA)
- 2 Pyrometry, Temperature Measurements, and Calibration II
G. Raymond Peacock, Temperatures.com, Inc. (USA)
Robert P. Madding, FLIR Systems, Inc. (USA)
- 3 Professional Standards I
Lisa West Åkerblom, FLIR Systems AB (Sweden)
Antonio Colantonio, Public Works and Government Services Canada
(Canada)
- 4 Professional Standards II
Lisa West Åkerblom, FLIR Systems AB (Sweden)
Antonio Colantonio, Public Works and Government Services Canada
(Canada)
- 5 Thermal Image Fusion
Herbert Kaplan, Honeyhill Technical Company (USA)
- 6 IR Neighbors: NIR, Visible and UV I
Herbert Kaplan, Honeyhill Technical Company (USA)
Jan K. Eklund, EKLUND INFRARED, Inc. (USA)
- 7 IR Neighbors: NIR, Visible and UV II
Herbert Kaplan, Honeyhill Technical Company (USA)
Jan K. Eklund, EKLUND INFRARED, Inc. (USA)
- 8 Research Topics
Morteza Safai, The Boeing Company (USA)
Gary L. Orlove, FLIR Systems, Inc. (USA)
- 9 Products and Processes
Andrés E. Rozlosnik, SI Termografía Infrarroja (Argentina)
Gregory R. Stockton, Stockton Infrared Thermographic Services, Inc.
(USA)

- 10 Environmental Investigations
Gregory R. Stockton, Stockton Infrared Thermographic Services, Inc.
(USA)
Andrés E. Rozlosnik, SI Termografía Infrarroja (Argentina)
- 11 NDT of Buildings and Civil Structures
Kathryn M. Knettel, United Space Alliance, LLC (USA)
Nicolas P. Avdelidis, EBETAM S.A. (Greece)
Timo T. Kauppinen, VTT (Finland)
- 12 NDT Numerical Analysis and Theory
Vladimir P. Vavilov, Tomsk Polytechnic University (Russia)
Douglas D. Burleigh, La Jolla Cove Consulting (USA)
K. Elliott Cramer, NASA Langley Research Center (USA)
- 13 NDT Methods and Applications
Douglas D. Burleigh, La Jolla Cove Consulting (USA)
Vladimir P. Vavilov, Tomsk Polytechnic University (Russia)
Ermanno G. Grinzato, Consiglio Nazionale delle Ricerche (Italy)
- 14 Materials Evaluation: Thermal and Fatigue Properties
Takahide Sakagami, Osaka University (Japan)
Pierre Bremond, Cedip Infrared Systems (France)
Jeff R. Brown, Hope College (USA)

